Search Notes

Application/Control No.			
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Applicant(s)/Patent under Reexamination

10/707,059 Examiner LIN, HSIEN-CHUNG
Art Unit

Chuck Huynh

2683

SEARCHED					
Class	Subclass	Date	Examiner		
455	575	8/5/2005	41		
455	462	8/5/2005	11		
341	22	8/5/2005	CH		
379	428.01	8/5/2005	ar		
455	567	8/5/2005	W		
340	7.51	8/5/2005	At.		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Class and Subclass	8/5/2005	W	
Text Searh	8/5/2005	W	